



# „Aplicatii ale nanotuburilor de carbon in realizarea de interconexiuni in circuitele integrate”

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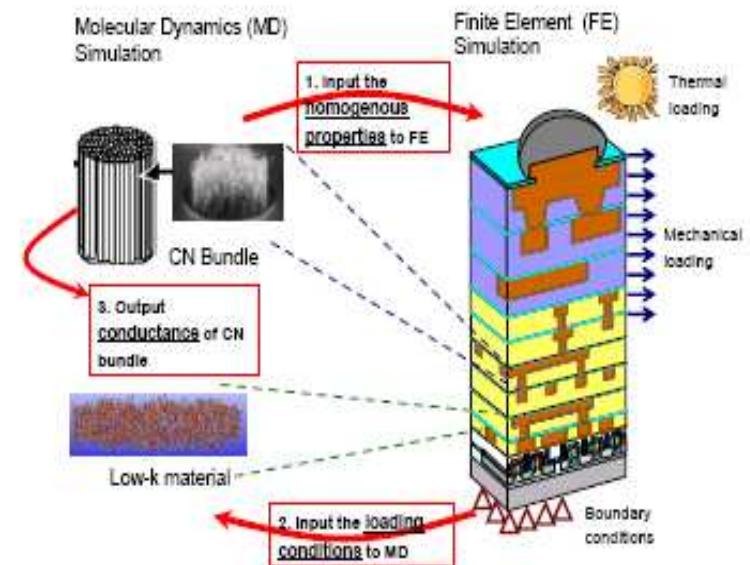
## 2005 Technology Roadmap for Semiconductors (ITRS):

- Interconexiunile traditionale nu mai satisfac cerintele funktionale impuse de viitoarele circuitele integrate .
- **Dimensiunile critice** ale tranzistoarelor sint sub **100nm** in timp ce interconexiunile au dimensiuni **micronice**.
- Cuprul care este inca solutia preferata pentru interconexiuni este susceptibil la **electromigratie** la densitati mari de curent si prezinta o **fiabilitate scazuta** atunci cand sectiunea interconexiunii scade la 100nm.
- Rezistivitatea electrica** a cuprului creste semnificativ pentru dimensiuni nanometrice ale interconexiunii
- Datorita proprietatilor fizice exceptionale **nanotuburile de carbon** se impun in mod natural ca o solutie de inlocuire a interconexiunilor de cupru

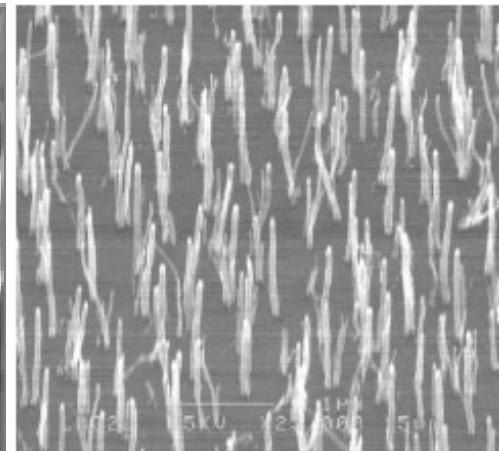
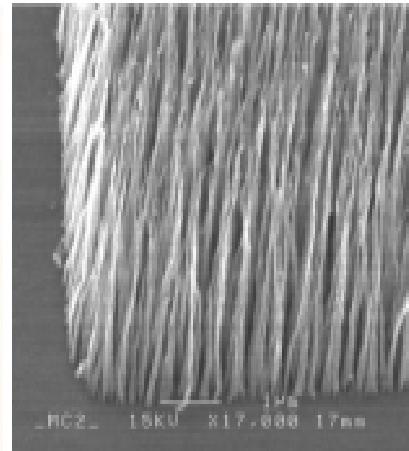
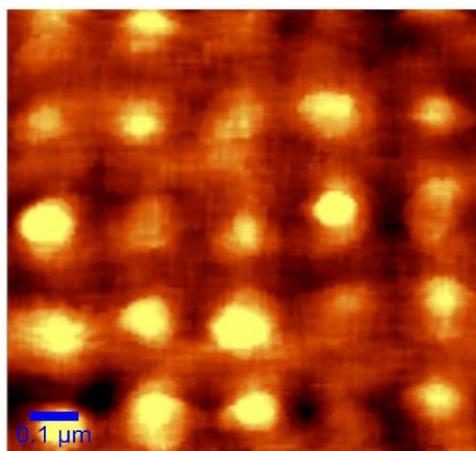
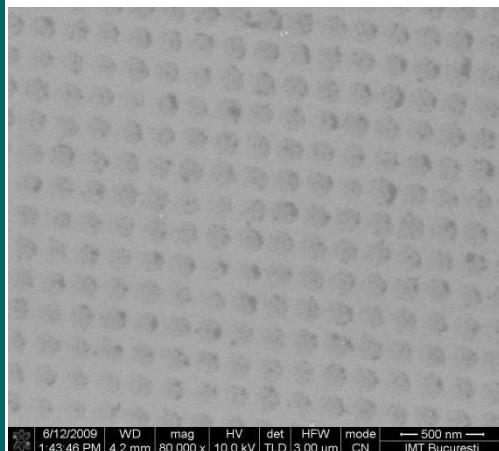


**Carbon nAnotube Technology for High-speed  
nExt-geneRation nano-InterconNEcts –  
CATHERINE**

[www.catherineproject.eu](http://www.catherineproject.eu)

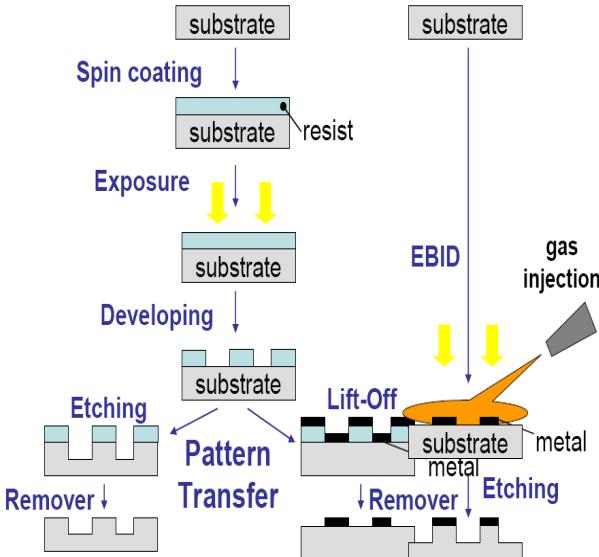


## Cresterea de nantuburi de carbon pe suprafete acoperite cu nanodoturi de Ni

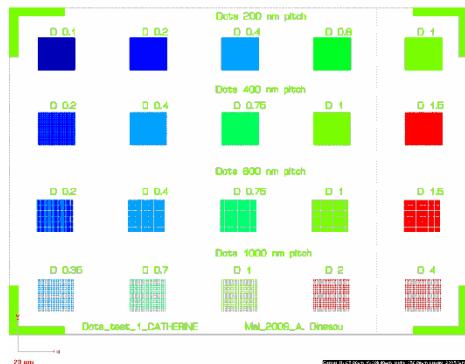




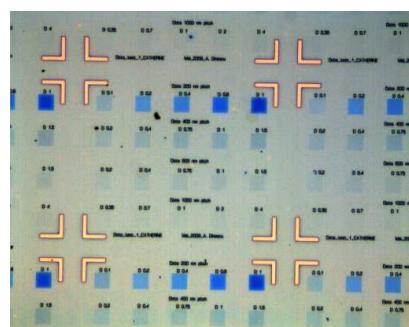
## Fabricarea nanodoturilor de Ni: litografie cu fascicul de electroni si lift - off



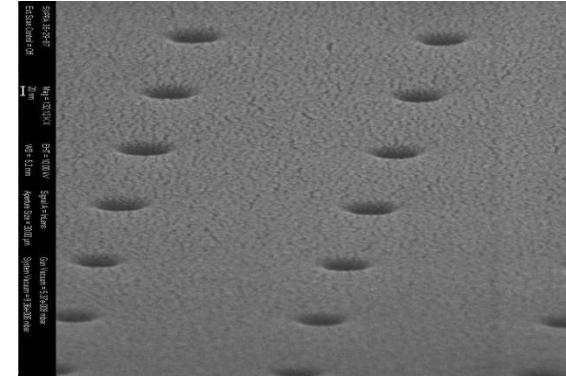
Principiul litografiei cu fascicul de electroni



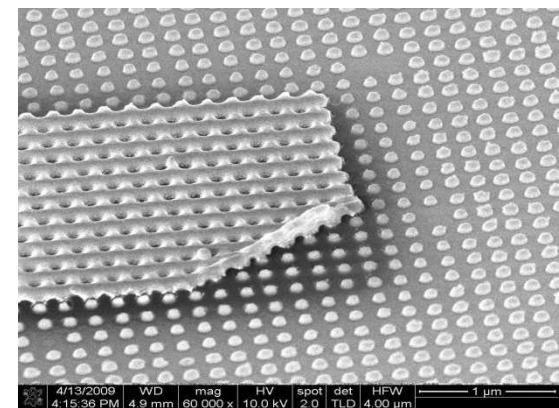
Layout-ul structurii test



Imagine optica a layout-ului expus in PMMA



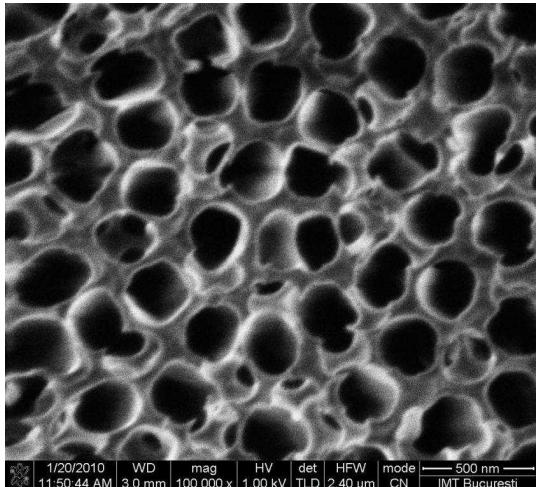
Micrografie SEM (proba inclinata la 45°) a gaurilor in PMMA



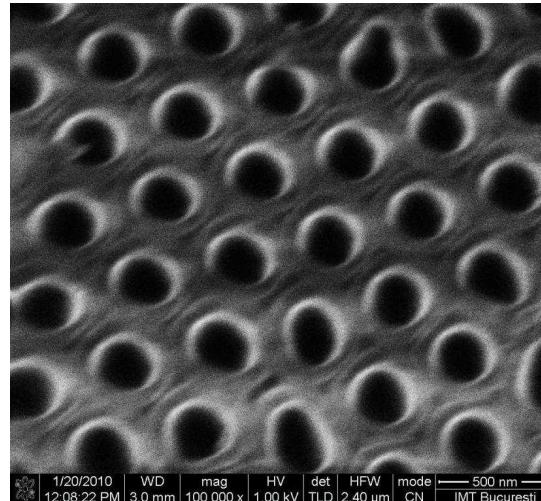
Arie acoperita cu nanodoturi de Ni dupa lift - off



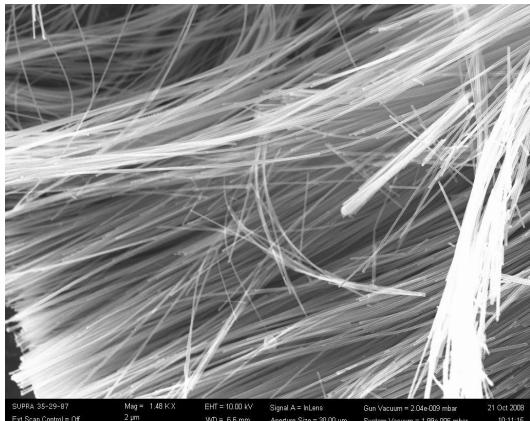
## Utilizarea membranelor poroase de alumina ca sabloane pentru cresterea nanotuburilor de carbon



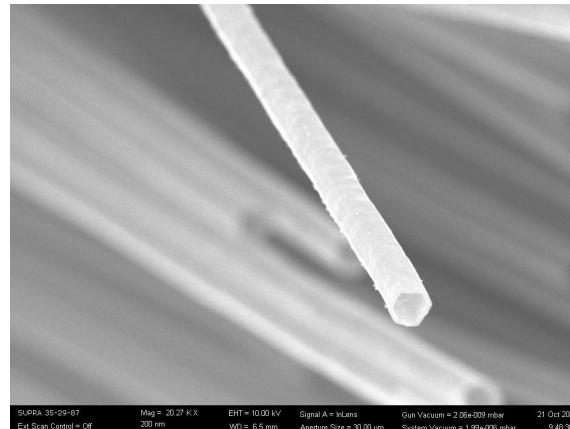
Membrana comerciala de alumina



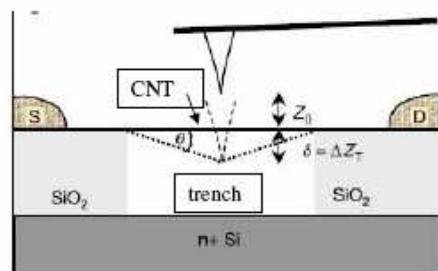
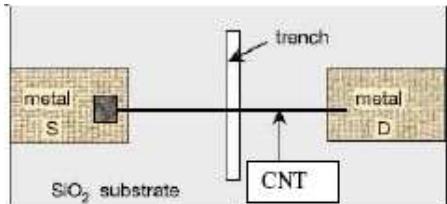
Membrana produsa de UPS Toulouse



Nanotuburi de carbon crescute in porii membranei de alumina (UNISAL Italia)



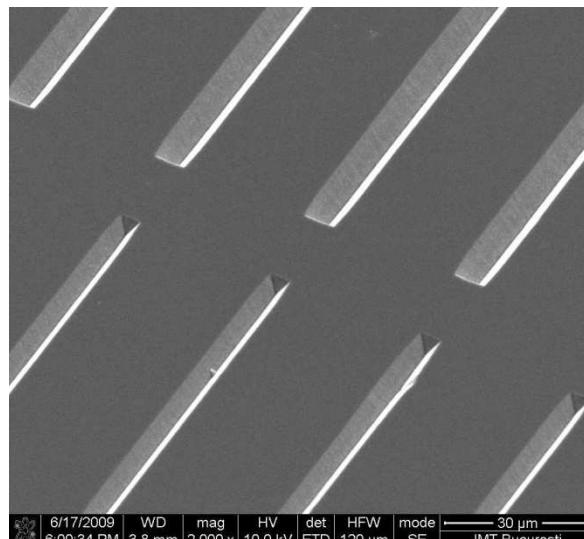
## Caracterizarea mecanica nanotuburilor de carbon.



Principiul metodei de caracterizare  
(TUD Delft)

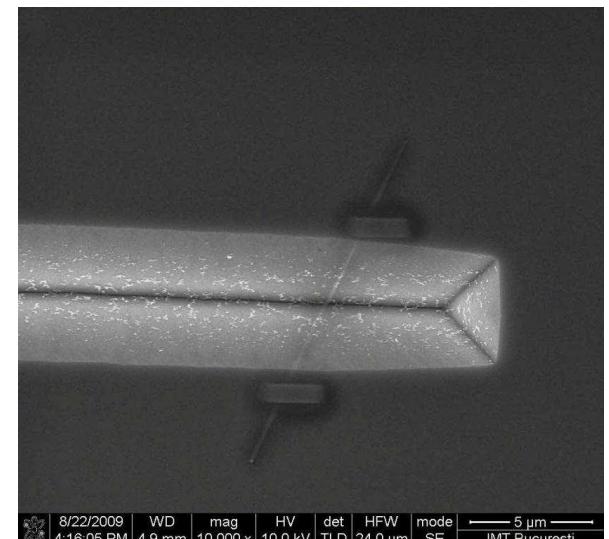
6/17/2009 | WD | mag | HV | det | HFW | mode | 30 µm  
6:00:34 PM | 3.8 mm | 2.000 x | 10.0 kV | ETD | 120 µm | SE | IMT Bucuresti

Straturi cu sectiune in V  
corodate in Siliciu



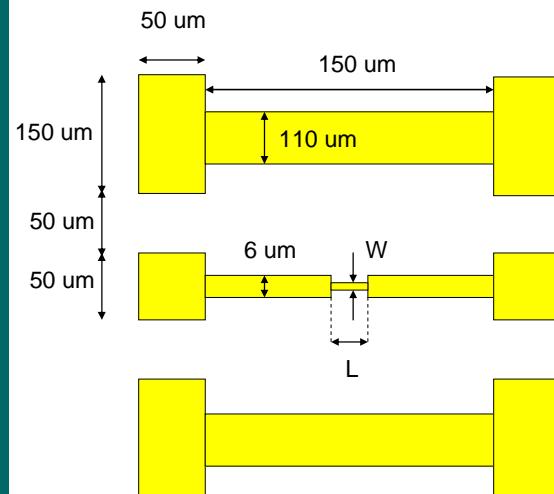
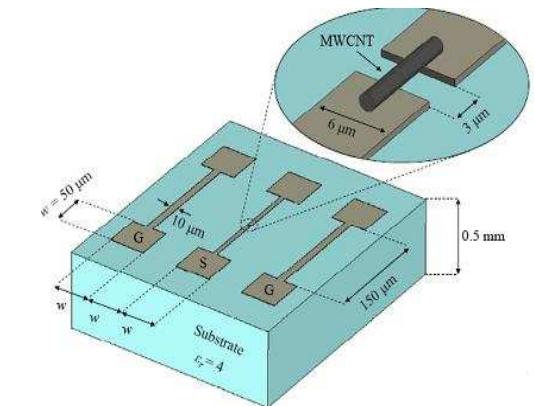
8/22/2009 | WD | mag | HV | det | HFW | mode | 5 µm  
4:16:05 PM | 4.9 mm | 10.000 x | 10.0 kV | TLD | 24.0 µm | SE | IMT Bucuresti

Utilizarea tehnicii EBID pentru  
fixarea nanotuburilor de carbon

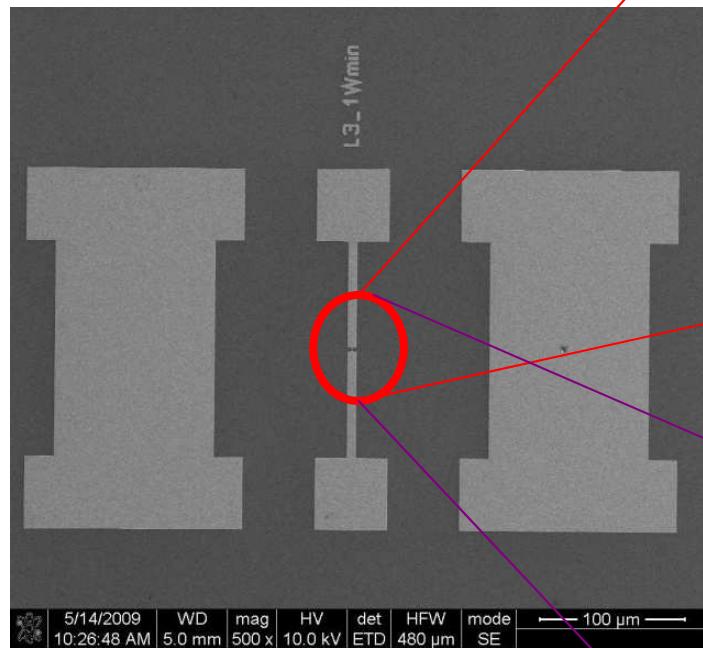




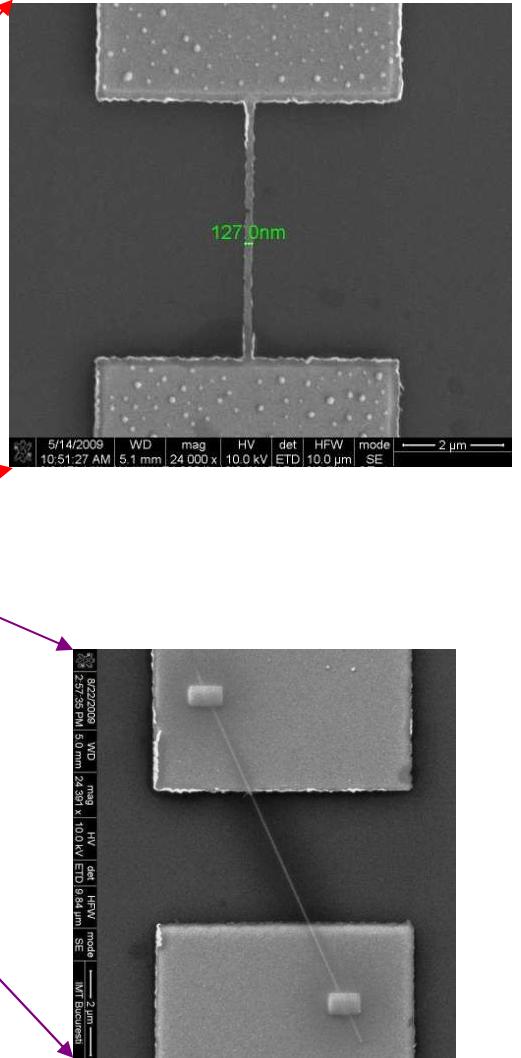
## Caracterizarea electrica a nanotuburilor de carbon.



Principiul metodei de masura  
(Universitatea Sapienza Roma)

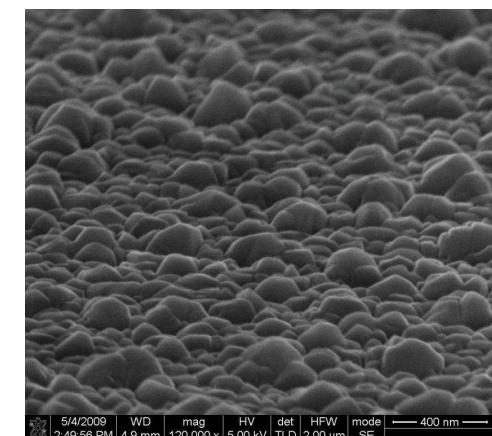
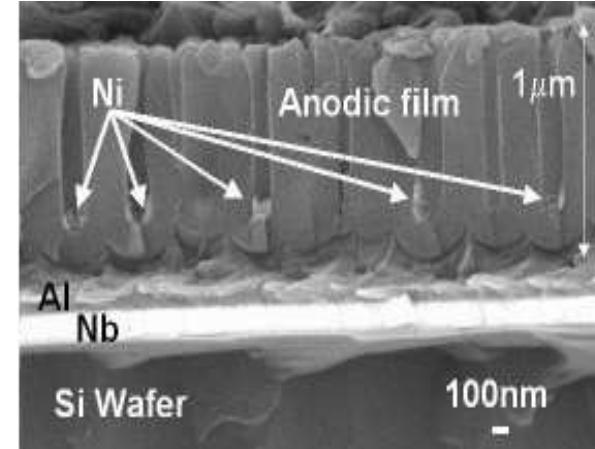
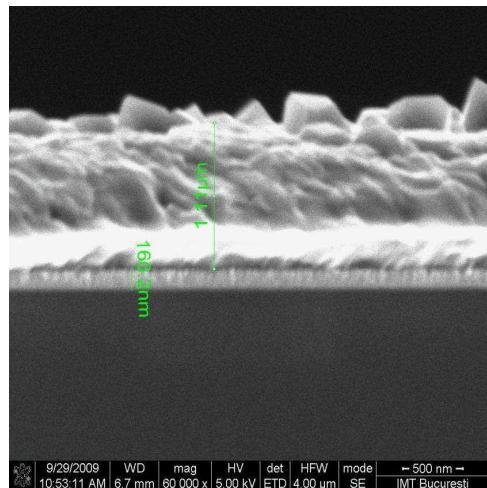


Structura de test destinata  
masuratorilor electrice de inalta  
frecventa

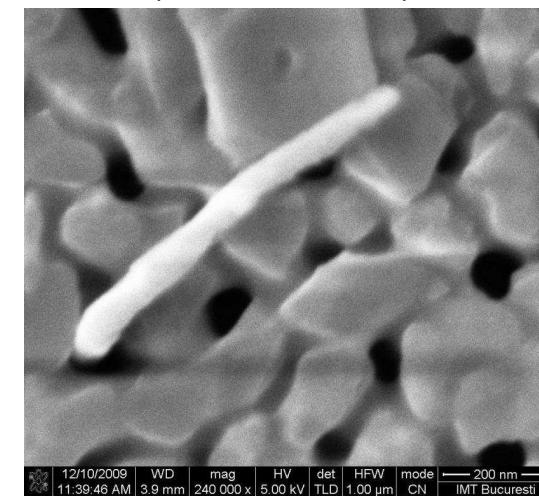




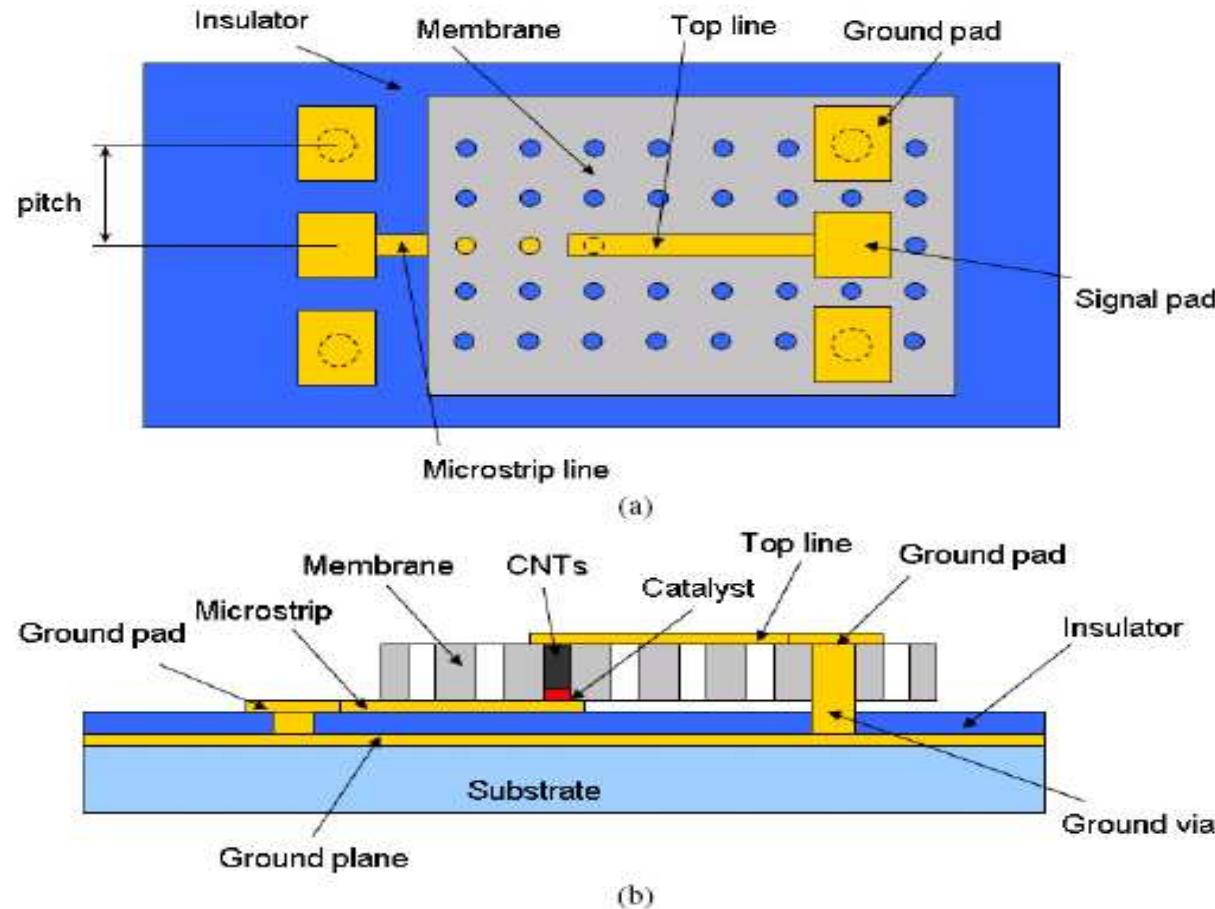
## Utilizarea membranelor poroase subtiri ( $W \leq 1\mu\text{m}$ ) ca sabloane pentru cresterea nanotuburilor de carbon



Micrografie SEm a suprafetei de Al



Nanotub de Carbon crescut in pori membranei  
INFN Frascati



Structura test propusa pentru masurarea caracteristicilor electrice de inalta frecventa ale nanotuburilor destinate vias-urilor locale